O(PE 2006 B)

SHEET 1 OF 1

Form PTO 1449 (Modified)		U.S. DEPAR DENT OF	COMMERCES	VATTY DOCKET NO. 291795US2PCT			SERIAL NO. 10/580,822			
			DEMAR							
LIST OF	REFE	RENCES CITED BY APPL	ICANT	APPLICANT	DDE at al					
LIST OF REFERENCES CITED BY APPLICANT				Janick BIGA	Leggue					
				FILING DATE			GROUP			
				May 26, 200						
		T		U.S. PATENT DO	DCUMEN 15	1	0.10		W INIC DATE	
EXAMINER INITIAL		DOCUMENT NUMBER	DATE		NAME	CLASS	SUB			
	AA								-	
	AB					ļ				
	AC									
	AD	<u> </u>				<u> </u>				
	AE	<u></u>								
	AF				· · · · · · · · · · · · · · · · · · ·					
	AG	_	· <del></del>							
	AH									
	AI				<u> </u>					
	AJ	<del> </del>			· · · · · · · · · · · · · · · · · · ·					
	AK	<del>  -</del>				-				
	AL					<del> </del>				
	AM	<del> </del>				<u> </u>				
	AN	<u> </u>				<u> </u>				
			FO	REIGN PATENT	DOCUMENTS					
		DOCUMENT DATE COUNTRY			COUNTRY	TRANSLATION YES NO				
	AO									
	AP		0							
	AQ									
	AR									
	AS									
	AT			•				J		
		OTHER REFE	RENCES (I	Including Autho	r, Title, Date, Pertinent	Pages, et	tc.)			
/MLB/	AV	BIGARRE J. et al., "TRAF INTERNATIONAL SOCIE	PPING OF E	LECTRICAL CH PTICAL ENGINE	ARGES AND LASER D ERING, vol. 4932, page	AMAGE", ( s 258-267,	PROCEED XP002289	INGS (	OF SPIE-THE	
/MLB	AW	KOZLOWSKI M. R. et al., ILLUMINATION", SPIE, v	"LUMINES ol. 3902, pa	CENCE INVEST ges 138-144, XP	IGATION OF S102 SUR 002289328, 2000	FACES DA	MAGED E	3Y 0.35	mm LASER	
/MLB/	AX	GOLDBERG M. et al., "DOSE EFFECTS OF CATHODOLUMINESCENCE IN Si02 LAYERS ON Si", MATERIALS SCIENCE AND ENGINEERING, vol. 842, pages 293-296, XP002289329, 1996								
/MLB/	AY	STEVENS KALCEFF M. A., "CATHODOLUMINESCENCE MICROCHARACTERIZATION OF THE DEFECT STRUCTURE OF IRRADIATED HYDRATED AND ANHYDROUS FUSED SILICON DIOXIDE", PHYSICAL REVIEW B, vol. 57, pages 5674-5683, XP002289330, 1998								
/MLB/	AZ	REICHLING M., "NANOSECOND UV LASER PULSE INTERACTIONS WITH DIELECTRIC SINGLE CRYSTALS", PROCEEDINGS OF THE SPIE- THE INTERNATIONAL SOCIETY FOR OPTICAL ENGINEERING, vol. 3274, pages 2-9, XP002289331, 1998								
				Additional References sheet(s) attached						
Examiner	/Ma	Manuel L. Barbeel					Date Considered 09/29/2007			
*Examiner: In conformance	itial if r	reference is considered, who considered. Include copy	ether or not of this form	citation is in con-	formance with MPEP 60 unication to applicant.	9; Draw lir	e through	citation	if not in	

OCT, 0-2 2006

SHEET 1 OF 1

Form PTO 1449		U.S. DEPARTMENT OF COMMERCE PATENT AND REDEMARK OF THE		ATTY DOCKET NO.			SERIAL NO.			
(Modified)		PATENTAND	MOENTA					10/580,822		
				APPLICANT						
LIST OF REFERENCES CITED BY APPLICANT				Janick BIGARRE, et al.						
				FILING DATE			GROUP			
				May 26, 2006						
			1	U.S. PATENT DO	CUMENTS					
EXAMINER INITIAL		DOCUMENT NUMBER	DATE		NAME	CLASS	SUB FILING DATE CLASS IF APPROPRIATE			
	AA					<u> </u>				
	AB					ļ				
	AC									
	AD									
	AE									
	AF									
	AG		_							
	АН									
	Al									
	AJ									
	AK									
	AL									
	AM									
	AN									
			FO	REIGN PATENT I	DOCUMENTS					
	DOCUMENT DATE			COUNTRY			TRANSLATION YES NO			
	AO									
	AP									
	AQ									
	AR					-				
	AS									
	AT									
			•	•	, Title, Date, Pertinent	•	•			
/MLB/	AV	BIGARRE J. et al., "TRA INTERNATIONAL SOCI	PPING OF E	LECTRICAL CHA	ARGES AND LASER D	AMAGE",	PROCEED XP002289	INGS C	OF SPIE-THE	
/MLB	AW	KOZLOWSKI M. R. et a ILLUMINATION", SPIE,	., "LUMINES	CENCE INVESTI	GATION OF SI02 SUR					
/MLB/	AX	GOLDBERG M. et al., "DOSE EFFECTS OF CATHODOLUMINESCENCE IN Si02 LAYERS ON Si", MATERIALS SCIENCE AND ENGINEERING, vol. 842, pages 293-296, XP002289329, 1996								
/MLB/	AY	STEVENS KALCEFF M. A., "CATHODOLUMINESCENCE MICROCHARACTERIZATION OF THE DEFECT STRUCTURE OF IRRADIATED HYDRATED AND ANHYDROUS FUSED SILICON DIOXIDE", PHYSICAL REVIEW B, vol. 57, pages 5674-5683, XP002289330, 1998								
/MLB/	AZ	REICHLING M., "NANO	REICHLING M., "NANOSECOND UV LASER PULSE INTERACTIONS WITH DIELECTRIC SINGLE CRYSTALS", PROCEEDINGS OF THE SPIE- THE INTERNATIONAL SOCIETY FOR OPTICAL ENGINEERING, vol. 3274, pages 2-9,							
				Additional References sheet(s				sheet(s) attached		
Examiner	/Ma	anuel L. Barbee/					Date Considered 09/29/2007			
*Examiner: In conformance	itial if r	reference is considered, work considered. Include cop	hether or not y of this form	citation is in confe with next commu	ormance with MPEP 60 nication to applicant.	9; Draw lir	e through	citation	if not in	